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- B13-O-01 High Spatial/Energy Resolution Cathodoluminescence Spectroscopy: Powerful Tool for Precise Characterization of Nanostructures
Xuewen Fu, Zhimin Liao and Dapeng Yu. Department of Physics, Laboratory for Nanostructures and Low-dimensional Physics, Peking Universityi31

- B13-O-02 Electron Channeling Contrast Imaging: A Powerful Technique to Quantitative Microstructure Characterization in the SEM
Ivan Gutierrez-Urrutia. Research Center for Strategic Materials, National Institute for Materials Sciencei32

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●B13-O-11	The Impact of Modern Scanning Electron Microscopy on Materials Science <i>Kaoru Sato¹, Masayasu Nagoshi² and Tomohiro Aoyama³.</i> ¹ JFE Steel, Chiba, ² JFE Steel, Kawasaki, ³ JFE Steel, Fukuyamai36